



EMC - scanner probes


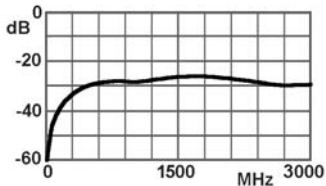

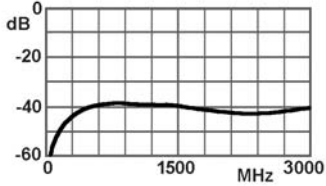

Fields of application:

- to detect modules, layout areas featuring critical frequencies
- to locate and evaluate magnetic and electric fields as vector quantities
- to determine emission sources, coupling mechanisms and functional chains
- to document, compare and evaluate module modifications
- to check the quality in the production process

Type of construction:

- electrically and/or magnetically shielded passive probe heads
- the active probe can be used with a 30 dB preamplifier
- probe body output with SMA-connector system on RG 174 cable basis

AVAILABLE SCANNER PROBE HEADS

Type	Description	Characteristic
	<p>RFS-R 50 The near field probe is suitable for measuring high-frequency fields of 30 MHz to 3 GHz at a short distance from the unit under test of up to approx. 3 cm.</p> <p>Frequency: 30 MHz to 3 GHz Overall length: ca. 55 mm Diameter: approx 10 mm</p>	
	<p>RFS-B 3 The near field probe is used to detect H-fields that emerge vertically from the surface of PCBs. It allows measurements in confined spaces such as between large components of switching controllers.</p> <p>Frequency: 30 MHz to 3 GHz Overall length: ca. 55 mm Diameter: approx 2 mm</p>	
	<p>RFS-E 3 Design structures, larger components and supply areas couple out E-fields via their surfaces. Such E-fields can be detected with the 6 x 6 mm underside of the near field probe.</p> <p>Frequency: 30 MHz to 3 GHz Overall length: 55 mm Electrode surface: approx. 4 x 4 mm</p>	